

03/04

SHEET 1 OF 1

Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 250227US-2X DIV		SERIAL NO. New DIV. Appln.		
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT Shinji IINO, et al.				
				FILING DATE Herewith		GROUP 2829		
U.S. PATENT DOCUMENTS								
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE	
Ple	AA	5,258,654	11/02/93	P.S. Roberts, et al.				
	AB	5,773,987	06/30/98	T.T. Montoya				
	AC	5,523,633	06/04/96	N. Imaizumi, et al.				
	AD	4,851,707	07/25/89	D.S. Lindsay				
	AE	4,477,774	10/1984	Revirieux, Michel				
	AF	6,057,694	05/2000	Matsudo				
Ple	AG	5,936,419	08/1999	Chen				
	AH							
	AI							
	AJ							
	AK							
	AL							
	AM							
	AN							
	FOREIGN PATENT DOCUMENTS							
			DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO		
Ple	AO	11-242062	09/07/99	Japan (with English Abstract)		x		
	AP	JP 64-048038	02/1989	Japan				
	AQ							
	AR							
	AS							
	AT							
	AU							
	AV							
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)								
Ple	AW	Mark Bailey, et al. "A Micromachined Array Probe Card-Characterization" IEEE Transactions on Components, Packaging, and Manufacturing Technology-Part B, Vol. 18, No. 1, February, 1995 pgs. 184-191						
	AX							
	AY							
	AZ							
Examiner					<input type="checkbox"/> Additional References sheet(s) attached Date Considered 10/21/04			
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.								